

*“Exploring possibilities of band gap measurement with off-axis EELS in TEM”*. Korneychuk S, Partoens B, Guzzinati G, Ramaneti R, Derluyn J, Haenen K, Verbeeck J, *Ultramicroscopy* **189**, 76 (2018). <http://doi.org/10.1016/J.ULTRAMIC.2018.03.021>